

# Computer Simulation

## Module 8: Input Data Analysis

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Goodness-of-Fit Tests



# Lesson Overview

Last Time: Finished off (for now) point estimation by discussing the Method of Moments.

This Time: We'll finally start our material on goodness-of-fit tests.

Idea: Does the choice of a particular simulation input distribution actually reflect reality?



At this point, we've guessed a reasonable distribution and then estimated the relevant parameters. Now let's conduct a formal test to see just how successful our toils have been.

In particular, test

$$H_0 : X_1, X_2, \dots, X_n \stackrel{\text{iid}}{\sim} \text{p.m.f. / p.d.f. } f(x)$$

at level of significance

$$\alpha \equiv P(\text{Reject } H_0 | H_0 \text{ true}) = P(\text{Type I error})$$

(usually,  $\alpha = 0.05$  or  $0.01$ ).

High-level view of a goodness-of-fit test procedure:

1. Divide the domain of  $f(x)$  into  $k$  sets, say,  $A_1, A_2, \dots, A_k$  (distinct points if  $X$  is discrete or intervals if  $X$  is continuous).
2. Tally the actual number of observations that fall in each set, say,  $O_i, i = 1, 2, \dots, k$ . If  $p_i \equiv P(X \in A_i)$ , then  $O_i \sim \text{Bin}(n, p_i)$ .
3. Determine the expected number of observations that would fall in each set if  $H_0$  were true, say,  $E_i = E[O_i] = np_i, i = 1, 2, \dots, k$ .
4. Calculate a test statistic based on the differences between the  $E_i$ 's and  $O_i$ 's. The **chi-squared g-o-f test** statistic is

$$\chi_0^2 \equiv \sum_{i=1}^k \frac{(O_i - E_i)^2}{E_i}.$$

5. A large value of  $\chi_0^2$  indicates a bad fit.

We *reject*  $H_0$  if  $\chi_0^2 > \chi_{\alpha, k-1-s}^2$ , where

- $s$  is the number of unknown parameters from  $f(x)$  that have to be estimated. E.g., if  $X \sim \text{Nor}(\mu, \sigma^2)$ , then  $s = 2$ .
- $\chi_{\alpha, \nu}^2$  is the  $(1 - \alpha)$  quantile of the  $\chi_\nu^2$  distribution, i.e.,  
 $P(\chi_\nu^2 < \chi_{\alpha, \nu}^2) = 1 - \alpha$ .

If  $\chi_0^2 \leq \chi_{\alpha, k-1-s}^2$ , we *fail to reject*  $H_0$ .

## Remarks:

- Usual recommendation from baby stats class: For the  $\chi^2$  g-o-f test to work, pick  $k, n$  such that  $E_i \geq 5$  and  $n$  at least 30.
- If the d.f.  $\nu = k - 1 - s$  happens to be very big, then

$$\chi_{\alpha, \nu}^2 \approx \nu \left[ 1 - \frac{2}{9\nu} + z_{\alpha} \sqrt{\frac{2}{9\nu}} \right]^3,$$

where  $z_{\alpha}$  is the appropriate standard normal quantile.

- Other g-o-f tests: Kolmogorov–Smirnov, Anderson–Darling, Shapiro–Wilk, etc.

**Baby Example:** Test  $H_0$ :  $X_i$ 's are  $\text{Unif}(0,1)$ . Suppose we have  $n = 1000$  observations divided into  $k = 5$  intervals.

interval	$[0,0.2]$	$(0.2,0.4]$	$(0.4,0.6]$	$(0.6,0.8]$	$(0.8,1.0]$
$E_i$	200	200	200	200	200
$O_i$	179	208	222	199	192

Turns out that  $\chi_0^2 \equiv \sum_{i=1}^k \frac{(O_i - E_i)^2}{E_i} = 5.27$ .

Let's take  $\alpha = 0.05$ . There are no unknown parameters, so  $s = 0$ .  
Then  $\chi_{\alpha, k-1-s}^2 = \chi_{0.05, 4}^2 = 9.49$ .

Since  $\chi_0^2 \leq \chi_{\alpha, k-1-s}^2$ , we fail to reject  $H_0$ .  $\square$

**Discrete Example:** The number of defects in printed circuit boards is hypothesized to follow a  $\text{Geometric}(p)$  distribution. A random sample of  $n = 70$  printed boards has been collected, and the number of defects observed.

# defects	frequency
1	34
2	18
3	2
4	9
5	7
<hr/>	
	70

We'll test  $H_0$ : The observations are  $\text{Geom}(p)$ .



Start by estimating  $p$  via the MLE. The likelihood function is

$$L(p) = \prod_{i=1}^n f(x_i) = \prod_{i=1}^n (1-p)^{x_i-1} p = (1-p)^{\sum_{i=1}^n x_i - n} p^n$$

$$\ln(L(p)) = \left( \sum_{i=1}^n x_i - n \right) \ln(1-p) + n \ln(p)$$

$$\frac{d \ln(L(p))}{dp} = \frac{-\sum_{i=1}^n x_i + n}{1-p} + \frac{n}{p} = 0.$$

Solving for  $p$  gives the MLE

$$\hat{p} = \frac{1}{\bar{X}} = \frac{70}{1(34) + 2(18) + 3(2) + 4(9) + 5(7)} = 0.476.$$

Let's get the g-o-f test statistic,  $\chi_0^2$ . We'll make a little table, assuming  $\hat{p} = 0.476$  is correct. By the Invariance Property of MLEs (this is why we learned it!), the expected number of boards having a certain value  $x$  is  $E_x = nP(X = x) = n(1 - \hat{p})^{x-1}\hat{p}$ . Note that I'll combine the entries in the last row ( $\geq 5$ ) so the probabilities add up to one.

$x$	$P(X = x)$	$E_x$	$O_x$
1	0.4762	33.33	34
2	0.2494	17.46	18
3	0.1307	9.15	2
4	0.0684	4.79	9
$\geq 5$	0.0752	5.27	7
	1.0000	70	70

Well, we really ought to combine the last two cells too, since  $E_4 = 4.79 < 5$ . Let's do so to get the following improved table.

$x$	$P(X = x)$	$E_x$	$O_x$
1	0.4762	33.33	34
2	0.2494	17.46	18
3	0.1307	9.15	2
$\geq 4$	0.1436	10.06	16
	1.0000	70	70

Thus, the test statistic is

$$\chi_0^2 = \sum_{x=1}^4 \frac{(E_x - O_x)^2}{E_x} = \frac{(33.33 - 34)^2}{33.33} + \dots = 9.12.$$

Let  $k = 4$  denote the number of cells (that we ultimately ended up with), and let  $s = 1$  denote the number of parameters we had to estimate.

Suppose the level  $\alpha = 0.05$ . Then we compare  $\chi_0^2$  against  $\chi_{\alpha, k-1-s}^2 = \chi_{0.05, 2}^2 = 5.99$ .

Since  $\chi_0^2 > \chi_{\alpha, k-1-s}^2$ , we reject  $H_0$ . This means that the number of defects probably isn't geometric.  $\square$

# Summary

This Time: We had the fits — goodness-of-fits, that is! We did a high-level overview and then a couple of easy examples.

Next Time: We'll apply a g-o-f test to the exponential distribution.



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Exponential Example



# Lesson Overview

Last Time: Had a high-level discussion of chi-square g-o-f tests and did some easy examples.

This Time: We'll do a g-o-f test for the exponential distribution.

The same general recipe can be applied to other distributions.





**Continuous Distributions:** For the continuous case, let's denote the intervals  $A_i \equiv (a_{i-1}, a_i]$ ,  $i = 1, 2, \dots, k$ . For convenience, we choose the  $a_i$ 's to ensure that we have equal-probability intervals, i.e.,

$$p_i = P(X \in A_i) = P(a_{i-1} < X \leq a_i) = 1/k \quad \text{for all } i.$$

In this case, we immediately have  $E_i = n/k$  for all  $i$ ; and then

$$\chi_0^2 = \sum_{i=1}^k \frac{(O_i - (n/k))^2}{n/k}.$$

The issue is that the  $a_i$ 's might depend on unknown parameters.

**Example:** Suppose that we're interested in fitting a distribution to a series of interarrival times. Could they be *Exponential*?

$$H_0 : X_1, X_2, \dots, X_n \stackrel{\text{iid}}{\sim} \text{Exp}(\lambda).$$

Let's do a  $\chi^2$  g-o-f test with *equal-probability intervals*. This amounts to choosing  $a_i$ 's such that

$$F(a_i) = P(X \leq a_i) = 1 - e^{-\lambda a_i} = \frac{i}{k}, \quad i = 1, 2, \dots, k.$$

$$a_i = -\frac{1}{\lambda} \ln\left(1 - \frac{i}{k}\right), \quad i = 1, 2, \dots, k.$$

Great, but  $\lambda$  is unknown (so we'll estimate  $s = 1$  parameter).

Good News: We know that the MLE is  $\hat{\lambda} = 1/\bar{X}$ . Thus, by the Invariance Property, the MLEs of the  $a_i$ 's are

$$\hat{a}_i = -\frac{1}{\hat{\lambda}} \ln\left(1 - \frac{i}{k}\right) = -\bar{X} \ln\left(1 - \frac{i}{k}\right), \quad i = 1, 2, \dots, k.$$

Continue Example: Suppose that we take  $n = 100$  observations and divide them into  $k = 5$  equal-prob intervals. Further suppose that sample mean based on the 100 observations is  $\bar{X} = 9.0$ .

$$\hat{a}_i = -9.0 \ln\left(1 - 0.2i\right), \quad i = 1, \dots, 5.$$

Suppose we determine which interval each of the 100 observations belongs to and tally them up to get the  $O_i$ 's.

interval $(a_{i-1}, a_i]$	$O_i$	$E_i = \frac{n}{k}$
$(0, 2.01]$	25	20
$(2.01, 4.60]$	27	20
$(4.60, 8.25]$	23	20
$(8.25, 14.48]$	13	20
$(14.48, \infty)$	12	20
	100	100

$$\chi_0^2 = \sum_{i=1}^k \frac{(O_i - E_i)^2}{E_i} = 9.80$$

$$\chi_{\alpha, k-1-s}^2 = \chi_{0.05, 3}^2 = 7.81$$

So we reject  $H_0$ . These observations ain't Expo.  $\square$

# Summary

This Time: We implemented a chi-square goodness-of-fit test for the exponential distribution... easy as pie!

Next Time: We'll do the same for a Weibull distribution. This takes a little more work than the Expo, but it's a more-robust g-o-f test.

